

## Christoph T. Koch - Extended Abstracts in Proceedings

Institute for Experimental Physics, Ulm University, 89069 Ulm, Germany  
Tel: +49 731 50 36400 , email: christoph.koch@uni-ulm.de  
URL: elim.physik.uni-ulm.de

**2000**

1. C.T. Koch and J.M. Zuo, "Comparison of multislice programs for HRTEM simulations and the bloch wave method", *Microsc. Microanal.* **6**, Suppl. 2: Proceedings (Springer New York 2000), p. 126-127

**2001**

2. C.T. Koch and J.C.H. Spence, "Reconstruction of the projected potential from a through voltage series of dynamical electron diffraction patterns including absorption", *Microsc. Microanal.* **7**, Suppl. 2: Proceedings (Springer New York 2001), p. 914-915
3. J.C.H. Spence and C.T. Koch, "Alchemi as Holography", *Microsc. Microanal.* **7**, Suppl. 2: Proceedings (Springer New York 2001), p. 350-351

**2002**

4. C.T. Koch and J.C.H. Spence, "Automated Solution of Nanocrystal Structures from CBED Patterns", In: Proceedings of the 15th International Congress on Electron Microscopy, (Eds.) Engelbrecht, J., Sevell, T., Witcomb, M., Cross, R., Richards, P., Microscopy Society of Southern Africa, Onderstepoort (2002)

**2003**

5. C.T. Koch, M. Rühle, "Numerical Nanodiffraction of Amorphous Grain Boundary Films", MC2003, Proc. 31st Conference Deutsche Gesellschaft für Elektronenmikroskopie, Dresden, Germany 7.-12.9.2003, Eds.: Th. Gemming, M. Lehmann, H. Lichte, K. Wetzig, *Microsc. Microanal.* **9** (Suppl. 3), 2003, 56-57

**2004**

6. C.T. Koch, S. Bhattacharyya, A. Subramaniam and M. Rühle, "Determining thermodynamic and structural parameters of thin amorphous intergranular films by electron diffraction", Proceedings of the 13th European Microscopy Congress, Vol. II (Belgian Society for Microscopy 2004), p. 37-38
7. C.T. Koch, "Solving the phase problem for electron diffraction on non centrosymmetric membrane protein structures", Proceedings of the 13th European Microscopy Congress, Vol. III (Belgian Society for Microscopy 2004), p. 247-248
8. C.T. Koch, S. Bhattacharyya, A. Subramaniam and M. Rühle, "Assessing thermodynamic properties of amorphous nanostructures by energy filtered electron diffraction", *Microsc. Microanal.* **10**, Suppl. 2: Proceedings (Springer New York 2004), p. 254-255
9. C.T. Koch, "Solving the phase problem for electron diffraction of non centrosymmetric two dimensional organic crystals using the example of membrane proteins", *Microsc. Microanal.* **10**, Suppl. 2: Proceedings (Springer New York 2004), p. 414-415

**2006**

10. C.T. Koch, S. Bhattacharyya and M. Rühle, "Diffraction Tomography and its Application to Intergranular Glassy Films in Ceramics", Proceedings of the 16th International Microscopy Congress 2006, held Sept. 3-8 in Sapporo, Japan. (International Federation of Societies in Microscopy, 2006) p. 999-999
11. S. Bhattacharyya, C.T. Koch and M. Rühle, "Measuring projected potential profiles across interfaces by reconstructing the exit face wave function from through focal series images", Proceedings of the 16th International Microscopy Congress

2006, held Sept. 3-8 in Sapporo, Japan. (International Federation of Societies in Microscopy, 2006) p. 1138-1138

12. E. Essers, R. Höschen, M. Matijevic, G. Benner and C.T. Koch, "Requisites for Ultimate Energy Resolution EELS and Band Gap Measurements in TEM", Proceedings of the 16th International Microscopy Congress 2006, held Sept. 3-8 in Sapporo, Japan. (International Federation of Societies in Microscopy, 2006) p. 810-810
13. W. Sigle, V. Srot, L. Gu, C.T. Koch, R. Höschen, E. Essers, M. Matijewic, G. Benner, A. Thesen and M. Rühle, "Low-loss electron spectroscopy using monochromated electrons", Proceedings of the 16th International Microscopy Congress 2006, held Sept. 3-8 in Sapporo, Japan. (International Federation of Societies in Microscopy, 2006) p. 811-811
14. L. Gu, V. Srot, W. Sigle, C.T. Koch, F. Scholz, C. Kirchner, S.B. Thapa and M. Rühle, "EELS studies of the bandgap in GaN using monochromated electrons", Proceedings of the 16th International Microscopy Congress 2006, held Sept. 3-8 in Sapporo, Japan. (International Federation of Societies in Microscopy, 2006) p. 1484-1484
15. E. Essers, R. Höschen, M. Matijevic, G. Benner and C.T. Koch, "Requisites for Ultimate Energy Resolution EELS and Band Gap Measurements in TEM", *Microsc. Microanal.* 12, Suppl. 2: Proceedings (Cambridge University Press, Cambridge, UK, 2006) p. 1148-1149
16. S. Bhattacharyya, C.T. Koch and M. Rühle, "Determination of projected potential profiles across interfaces using through focal series reconstruction", *Microsc. Microanal.* 12, Suppl. 2: Proceedings (Cambridge University Press, Cambridge, UK, 2006) p. 1016-1017

## 2007

17. W. Sigle, V. Srot, L. Gu, C.T. Koch, P.A. van Aken, "Band-gap measurements using electron energy-loss spectroscopy", 11th Frontiers of Electron Microscopy in Materials Science Conference (FEMMS2007), September 23-28 (2007), Sonoma, California, USA.
18. P.A. van Aken, C.T. Koch, W. Sigle, R. Höschen, M. Rühle, E. Essers, G. Benner, M. Matijevic, "The Sub-Electron-Volt-Sub-nstrom-Microscope (SESAM): Pushing the Limits in Monochromated and Energy-Filtered TEM", *Microscopy and Microanalysis* 2007 Meeting, August 5-9 (2007), Fort Lauderdale, Florida, USA. *Microscopy and Microanalysis* **13** (Suppl 2) (2007) 862CD-863CD.
19. L. Gu, V. Srot, W. Sigle, C.T. Koch, P.A. van Aken, "VEELS bandgap measurements using monochromated electrons", Electron Microscopy and Analysis Group Conference 2007 (EMAG 2007), September 03 - 07 (2007), Glasgow, UK.
20. C.T. Koch, B. Rahmati, P.A. van Aken, M. Bäurer, M. Hoffmann, "Mapping Grain Boundary Potentials by Inline Electron Holography", MC2007, Proc. 33rd Conference Deutsche Gesellschaft für Elektronenmikroskopie, Saarbrücken, Germany 2.-7.9.2007, Eds.: Th. Gemming, U. Hartmann, P. Mestres, P. Walther, *Microsc. Microanal.* 13 (Suppl. 3), 2007, 334-335
21. C.T. Koch, "Solving the Dynamic Inversion Problem", MC2007, Proc. 33rd Conference Deutsche Gesellschaft für Elektronenmikroskopie, Saarbrücken, Germany 2.-7.9.2007, Eds.: Th. Gemming, U. Hartmann, P. Mestres, P. Walther, *Microsc. Microanal.* 13 (Suppl. 3), 2007, 118-119
22. E. Essers, M. Matijevic, G. Benner, R. Höschen, W. Sigle, C.T. Koch, "Analytical Performance of the SESAM Microscope", MC2007, Proc. 33rd Conference Deutsche Gesellschaft für Elektronenmikroskopie, Saarbrücken, Germany

- 2.-7.9.2007, Eds.: Th. Gemming, U. Hartmann, P. Mestres, P. Walther, Microsc. Microanal. 13 (Suppl. 3), 2007, 18-19
23. W. Sigle, L. Gu, V. Srot, C.T. Koch, P.A. van Aken, "Low-loss EELS with Monochromated Electrons", MC2007, Proc. 33rd Conference Deutsche Gesellschaft für Elektronenmikroskopie, Saarbrücken, Germany 2.-7.9.2007, Eds.: Th. Gemming, U. Hartmann, P. Mestres, P. Walther, Microsc. Microanal. 13 (Suppl. 3), 2007, 54-55
- 2008**
24. C.T. Koch, B. Rahmati, P.A. van Aken, "Nonlinear Electron Inline Holography", 14th European Microscopy Congress (EMC) 2008, September 01 - 05 (2008), Aachen, Vol. 2: Materials Science (Springer, Berlin Heidelberg), pp. 236-237
25. C.T. Koch, W. Sigle, J. Nelayah, L. Gu, V. Srot, and P.A. van Aken, "Sub-0.5 eV EFTEM Mapping using the Zeiss SESAM", 14th European Microscopy Congress (EMC) 2008, September 01 - 05 (2008), Aachen, Vol. 2: Materials Science (Springer, Berlin Heidelberg), pp. 447-448
26. C.T. Koch, "Quantitative TEM and STEM Simulations", 14th European Microscopy Congress (EMC) 2008, September 01 - 05 (2008), Aachen, Vol. 2: Materials Science (Springer, Berlin Heidelberg), pp. 93-94
27. C.T. Koch, P. Bellina, P.A. van Aken, "Software Precession Electron Diffraction", 14th European Microscopy Congress (EMC) 2008, September 01 - 05 (2008), Aachen, Vol. 2: Materials Science (Springer, Berlin Heidelberg), pp. 201-202
28. P.A. van Aken, J. Nelayah, L. Gu, W. Sigle, C.T. Koch, V. Srot, L. Pastoriza-Santos, L.M Liz-Marzan, "Low-loss EFTEM imaging of surface plasmon resonances in triangular silver nanoparticles" MRS Fall meeting 2008, December 1 - 5, 2008, Boston, USA.
29. W. Sigle, L. Gu, C. Koch, V. Srot, J. Nelayah, P.A. van Aken, "Application of Monochromated Electrons in EELS" Microscopy and Microanalysis 2008 Meeting, August 3-7, 2008, Albuquerque, New Mexico, USA.
30. B. Rahmati, G. Gregori, W. Sigle, C.T. Koch, P.A. van Aken, J. Maier, "Analytical and high-resolution TEM investigation of Boron-doped CeO<sub>2</sub>", 14th European Microscopy Congress (EMC) 2008, September 01 - 05 (2008), Aachen, Vol. 2: Materials Science (Springer, Berlin Heidelberg), pp. 565-566
31. J. Nelayah, L. Gu, W. Sigle, C.T. Koch, L. Pastoriza-Santos, L.M Liz-Marzan, P.A. van Aken, "Low-loss-energy EFTEM imaging of triangular silver nanoparticles", 14th European Microscopy Congress (EMC) 2008, September 01 - 05 (2008), Aachen, Vol. 2: Materials Science (Springer, Berlin Heidelberg), pp. 638-639
32. L. Gu, W. Sigle, C.T. Koch, V. Srot, J. Nelayah and P.A. van Aken, "Band gap mapping using monochromated electrons", 14th European Microscopy Congress (EMC) 2008, September 01 - 05 (2008), Aachen, Vol. 2: Materials Science (Springer, Berlin Heidelberg), pp. 381-382
- 2009**
33. C.T. Koch, B. Rahmati, W. Sigle, M. Shirpour, R. Merkle, J. Maier, and P.A. van Aken, "Mapping Grain Boundary Potentials in Ceramics by Nonlinear Inline Electron Holography and Impedance Spectroscopy" Microscopy Conference 2009, Aug. 30 - Sept. 4 (2009), Graz, Austria: G. Kothleitner, M. Leisch (Eds.), MC2009, Vol. 3 (Verlag TU Graz, Graz) pp. 329-330
34. B. Özdöl, C.T. Koch, P. Philipp, and P.A. van Aken, "Strain measurements on Si/SiGe heterosturctures using HRTEM" Microscopy Conference 2009, Aug. 30

- Sept. 4 (2009), Graz, Austria: G. Kothleitner, M. Leisch (Eds.), MC2009, Vol. 3 (Verlag TU Graz, Graz) pp. 447-448
35. N.Y. Jin-Phillipp, C.T. Koch, and P.A. van Aken, "EFTEM Tomography on Nanomaterials" Microscopy Conference 2009, Aug. 30 - Sept. 4 (2009), Graz, Austria: G. Kothleitner, M. Leisch (Eds.), MC2009, Vol. 1 (Verlag TU Graz, Graz) pp. 73-74
  36. B. Ögüt, W. Sigle, J. Nelayah, C.T. Koch, and P. A. van Aken, "Study of Surface Plasmon Resonances on complex 2D Ag Nanocavities by Low-Loss EFTEM Imaging", Microscopy Conference 2009, Aug. 30 - Sept. 4 (2009), Graz, Austria: G. Kothleitner, M. Leisch (Eds.), MC2009, Vol. 1 (Verlag TU Graz, Graz) pp. 131-132
  37. W. Sigle, J. Nelayah, C.T. Koch, B. Ögüt, and P.A. van Aken, "Surface plasmon resonance effects in a perforated Ag film studied by energy-filtering TEM" Microscopy Conference 2009, Aug. 30 - Sept. 4 (2009), Graz, Austria: G. Kothleitner, M. Leisch (Eds.), MC2009, Vol. 1 (Verlag TU Graz, Graz) pp. 111-112
  38. V. Srot, U.G.K. Wegst, P.A. van Aken, C.T. Koch, and U. Salzberger, "ELNES studies of abalone shell and CaCO<sub>3</sub> geological polymorphs" Microscopy Conference 2009, Aug. 30 - Sept. 4 (2009), Graz, Austria: G. Kothleitner, M. Leisch (Eds.), MC2009, Vol. 3 (Verlag TU Graz, Graz) pp. 287-288
- 2010**
39. C.T. Koch, "Measuring electron scattering factors by large angle rocking beam electron diffraction (LARBED)", *Acta Cryst. A* **66** (2010) s66
  40. C.T. Koch, "Quantitative Analysis of Crystal Defects: Towards 3-Dimensional Imaging of Charge Densities and Atomic Structure by Inline Electron Holography", *Microsc. Microanal. 16*, Suppl. 2 (2010) 1478-1479
  41. P.A. van Aken, W. Sigle, C.T. Koch, B. Ögüt, J. Nelayah, L. Gu, "Low-loss EFTEM Imaging of Surface Plasmon Resonances in Ag Nanostructure", *Microsc. Microanal. 16*, Suppl. 2 (2010) 1438-1439
  42. V. Srot, U.G.K. Wegst, U. Salzberger, C.T. Koch, P.A. van Aken, "ELNES Investigations of Interfaces in Abalone Shell", *Microsc. Microanal. 16*, Suppl. 2 (2010) 1218-1219
  43. V.B. Özdöl, C.T. Koch, P.A. van Aken, "Strain Mapping of 45 nm MOSFET by Dark-Field Inline Electron Holography", *Microsc. Microanal. 16*, Suppl. 2 (2010) 592-593
  44. N.Y. Jin-Phillipp, C.T. Koch, P.A. van Aken, "3D Elemental Mapping in Nanomaterials by Core-Loss EFTEM Tomography", *Microsc. Microanal. 16*, Suppl. 2 (2010) 1842-1843
  45. D. Abou-Ras, S.S. Schmidt, J. Kavalakkatt, M. Nichterwitz, J. Haarstrich, C.T. Koch, B. Schaffer and P.-P. Choi "Grain-boundary physics in Cu(In,Ga)Se<sub>2</sub> photovoltaic absorbers revealed by means of various electron microscopy techniques", 17th International Microscopy Congress - IMC17 Sept. 19-24 (2010), Rio de Janeiro, Brazil
  46. V. Srot, B. Bussmann, U. Salzberger, C.T. Koch, G. Cizmek and P.A. van Aken, "Analytical (S)TEM studies of human teeth", 17th International Microscopy Congress - IMC17 Sept. 19-24 (2010), Rio de Janeiro, Brazil
  47. P.A. van Aken, B. Ögüt, W. Sigle and C.T. Koch, "Excitation of Surface Plasmon Resonances in Nanostructured Ag Films", 17th International Microscopy Congress - IMC17 Sept. 19-24 (2010), Rio de Janeiro, Brazil

48. N. Y. Jin-Phillipp, C.T. Koch and P.A. van Aken, "Core-Loss EFTEM Tomography: 3D Elemental Mapping of Nanomaterials", 17th International Microscopy Congress - IMC17 Sept. 19-24 (2010), Rio de Janeiro, Brazil
49. V.B. Özdöl, C.T. Koch, P.A. van Aken, "Dark-field Inline Holography Approach to Map Strain in Semiconductor Devices" 17th International Microscopy Congress - IMC17 Sept. 19-24 (2010), Rio de Janeiro, Brazil
- 2011**
50. C.T. Koch, "Large-angle rocking-beam electron diffraction (LARBED)" Acta Cryst. A67 (2011) C696-C697
51. C.T. Koch, "Acquiring quasi-kinematic 3-dimensional electron diffraction data from a single specimen orientation by aberration-compensated large-angle rocking-beam electron diffraction" Microscopy Conference MC2011 (2011), IM4.413
52. W. Sigle, N. Talebi, B. Ögüt, L. Gu, R. Vogelgesang, C.T. Koch, and P.A. van Aken, "Surface plasmon eigenmodes in metallic nanostructures", Microscopy Conference MC2011 (2011), IM5.512
53. B. Ögüt, W. Sigle, N. Talebi, R. Vogelgesang, C.T. Koch and P.A. van Aken, "Plasmonic eigenmodes of rectangular slits in thin silver films" Microscopy Conference MC2011 (2011), IM5.P163
54. W. Sigle, S. Löffler, P. Schattschneider, R. Höschen, C.T. Koch, P. A. van Aken, "Sub-5 meV precision in plasmon mapping", Microscopy Conference MC2011 (2011), IM5.P173
55. V.B. Özdöl, C.T. Koch, P.A. van Aken, "Nanometer-scale characterization of strain-engineered semiconductor devices" Microscopy Conference MC2011 (2011), M2.232
56. D. Abou-Ras, S.S. Schmidt, R. Caballero, T. Unold, H.-W. Schock, C.T. Koch, B. Schaffer, M. Schaffer, P.-P. Choi, O. Cojocaru-Miredin, "High resolution grain boundary analysis of Cu(In,Ga)Se<sub>2</sub> thin films in solar cells" Microscopy Conference MC2011 (2011), M1.P508
57. V. Srot, B. Bussmann, U. Salzberger, C.T. Koch, G. Gizmek and P.A. van Aken, "Analytical TEM characterization of mineralized dental tissues" Microscopy Conference MC2011 (2011), L6.P352
58. V. Srot, B. Bussmann, U. Salzberger, C.T. Koch, G. Gizmek and P.A. van Aken, "Characterization of Dentine, Dentinal Tubules and Dentine-Enamel Function in Human Teeth by Advanced Analytical TEM", Microsc. Microanal. 17 (Suppl 2), (2011) 286-287
59. W. Sigle, L. Gu, N. Talebi, B. Ögüt, C.T. Koch, R. Vogelgesang, and P.A. van Aken, "EELS and EFTEM of Surface Plasmon in Metallic Nanostructures", Microsc. Microanal. 17 (Suppl 2), (2011) 762-763
60. V.B. Özdöl, C.T. Koch, P.A. van Aken, "Low-Dose Strain Mapping by Dark-Field Inline Electron Holography", Microsc. Microanal. 17 (Suppl 2), (2011) 1228-1229
61. D. Abou-Ras, S.S. Schmidt, R. Caballero, T. Unold, H.-W. Schock, C.T. Koch, B. Schaffer, M. Schaffer, P. Choi, O. Cojocaru-Miredin, "Confined and chemically flexible grain boundaries in Cu(In,Ga)Se<sub>2</sub> thin films", PVSEC-21 Technical Digest (2011) 3B-3O-01

**2012**

62. C.T. Koch, "Aberration-Compensated Large-Angle Rocking-Beam Electron Diffraction (LARBED)", Conference Proceedings APMC 10 / ICONN 2012 / ACMM 22 in Perth, Western Australia (2012) 1029.1-1029.2
63. C.T. Koch, "Electron Holography without a Biprism", Conference Proceedings APMC 10 / ICONN 2012 / ACMM 22 in Perth, Western Australia (2012) 594.1-594.2
64. K. Song, C.T. Koch, G.Y. Shin, J.K. Kim and S.H. Oh "Strain mapping of LED devices by dark-field inline electron holography", Conference Proceedings APMC 10 / ICONN 2012 / ACMM 22 in Perth, Western Australia (2012) 924.1-924.2
65. C.T. Koch, "4D Electron Diffraction by Large-Angle Rocking-Beam Electron Diffraction (LARBED)", European Microscopy Congress EMC2012 in Manchester, UK (2012), 138
66. C.T. Koch, "Full-Resolution Inline Electron Holography (FRIH)", European Microscopy Congress EMC2012 in Manchester, UK (2012), 139
67. V. Srot, U.G.K. Wegst, U. Salzberger, C.T. Koch and P.A. van Aken, "Interfaces and contacts in natural composite materials" European Microscopy Congress EMC2012 in Manchester, UK (2012), 476
68. V. Srot, B. Bussmann, U. Salzberger, C.T. Koch and P.A. van Aken, "Correlating microstructure and nanochemistry of human dental tissues" European Microscopy Congress EMC2012 in Manchester, UK (2012), 470
69. X. Mu, W. Sigle, C.T. Koch, A. Bach, D. Fischer, N. Toto, S. Neelamraju, C. Schön, M. Jansen and P.A. van Aken, "TEM study of the structural evolution of ionic solids from amorphous to polycrystalline phases in the case of alkali difluoride systems", European Microscopy Congress EMC2012 in Manchester, UK (2012)
70. W. van den Broek, C.T. Koch, "Feasibility study of atomic resolution tomography by charge flipping", European Microscopy Congress EMC2012 in Manchester, UK (2012)
71. N. Talebi, R. Vogelgesang, L. Gu, W. Sigle, C.T. Koch, B. Ögüt, M. Rohm, L.M. Liz-Marzan and P.A. van Aken, "Surface-plasmon modes and mode degeneracy in a triangular system", European Microscopy Congress EMC2012 in Manchester, UK (2012), 543

**2013**

72. C. Ophus, J. Ciston, P. Ercius, U. Dahmen, C.T. Koch, "Quantitative Reconstruction and Analysis of HRTEM Complex Exit Waves using Inline Holography", Microscopy and Microanalysis **19** (S2) (2013) 322-323
73. V. B. Özdöl, C.T. Koch, A. M. Minor, "Nanometer-scale characterization tools for strain-engineered semiconductor devices", Microscopy and Microanalysis **19** (S2), (2013) 1076-1077
74. K. Song, C.T. Koch, S.Y. Choi, H.N. Lee, S. Ryu, C.B. Eom, S.H. Oh, "Mapping of Two Dimensional Electron Gas at Atomically Abrupt Oxide Interfaces using Inline Electron Holography", Microscopy and Microanalysis **19** (S2), (2013) 1364-1365
75. W. Van den Broek and C.T. Koch, "Towards an experimental realization of inverse dynamical electron scattering", Proceedings of the Microscopy Conference MC2013 (2013) 53-54
76. W. Sigle, C.T. Koch, B. Ögüt, N. Talebi, P. A. van Aken, "Peak mapping in EFTEM", Proceedings of the Microscopy Conference MC2013 (2013) 176-177

77. C.T. Koch and F. Wang, "Towards automated solving of the dynamic inversion problem in electron diffraction for moderately thick crystals", Proceedings of the Microscopy Conference MC2013 (2013) 25-26
78. F. Wang, R. Pennington, C.T. Koch, "GPU - accelerated Bloch wave calculation for quantitative structure factor determination", Proceedings of the Microscopy Conference MC2013 (2013) 39-40
79. R. Pennington, C.T. Koch, "A modified Bloch - wave approach for dynamical scattering to limited order for structurally complex specimens", Proceedings of the Microscopy Conference MC2013 (2013) 63-64
80. R. Janzen, C.T. Koch, G. Schönhense, A. Parvizi, "Monochromatizing without filtering using dynamic fields without bunching: A new concept for d- TEM illumination", Proceedings of the Microscopy Conference MC2013 (2013) 93-94
81. C.T. Koch and W. Van den Broek, "Non - linear electron tomography", Proceedings of the Microscopy Conference MC2013 (2013) 256-257
82. D. Tyutyunnikov, C.T. Koch, P. van Aken, "Resolution Extension in Missing-wedge-free Dark-field Tomography", Proceedings of the Microscopy Conference MC2013 (2013) 277-278
83. B. Ögüt, R. Vogelgesang, W. Sigle, N. Talebi, C.T. Koch, P.A. van Aken, "Hybridized metal slit eigenmodes as an illustration of Babinet's principle", Proceedings of the Microscopy Conference MC2013 (2013) 445-446
84. C. Ozsoy Keskinbora, C.T. Koch, H.M. Benia, B. Bussmann, K. Kern, P.A. van Aken, "Electrostatic potential mapping in topological insulators by inline electron holography", Proceedings of the Microscopy Conference MC2013 (2013) 466-467